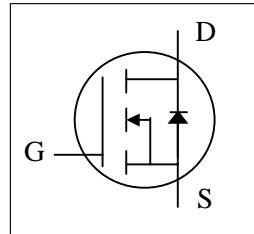
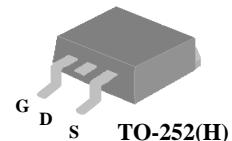




- ▼ Simple Drive Requirement
- ▼ Low On-resistance
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	80V
$R_{DS(ON)}$	8mΩ
$I_D$	60A



## Description

AP8N8R0 series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

TO-252 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for high current application due to the low connection resistance.

## Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	80	V
$V_{GS}$	Gate-Source Voltage	+20	V
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	60	A
$I_D @ T_C = 100^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	37.8	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	200	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation	52	W
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	2	W
$E_{AS}$	Single Pulse Avalanche Energy <sup>3</sup>	45	mJ
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	2.4	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient (PCB mount) <sup>4</sup>	62.5	°C/W



# AP8N8R0H

## Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=250\mu\text{A}$	80	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}$ , $I_{\text{D}}=30\text{A}$	-	-	8	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_{\text{D}}=250\mu\text{A}$	2	-	5	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=10\text{V}$ , $I_{\text{D}}=30\text{A}$	-	46	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=64\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	25	$\text{uA}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge	$I_{\text{D}}=30\text{A}$	-	42	67.2	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=40\text{V}$	-	13	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=10\text{V}$	-	11.5	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=40\text{V}$	-	15	-	ns
$t_r$	Rise Time	$I_{\text{D}}=30\text{A}$	-	58	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=6\Omega$	-	28	-	ns
$t_f$	Fall Time	$V_{\text{GS}}=10\text{V}$	-	63	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	2450	3920	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=40\text{V}$	-	930	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	35	-	pF
$R_g$	Gate Resistance	f=1.0MHz	-	1	2	$\Omega$

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=30\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_{\text{S}}=30\text{A}$ , $V_{\text{GS}}=0\text{V}$ ,	-	37	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge	dl/dt=100A/ $\mu\text{s}$	-	28	-	nC

## Notes:

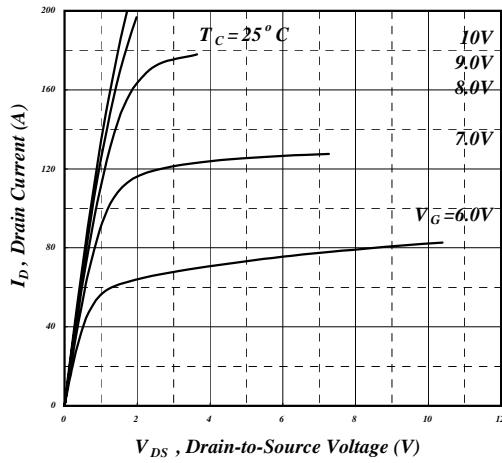
- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Starting  $T_j=25^\circ\text{C}$  ,  $V_{\text{DD}}=40\text{V}$  ,  $L=0.1\text{mH}$  ,  $R_G=25\Omega$
- 4.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

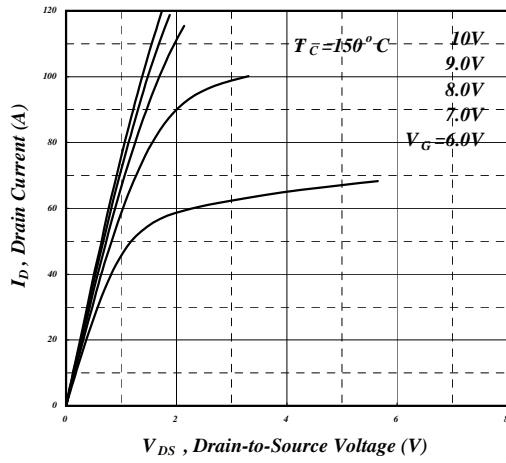
USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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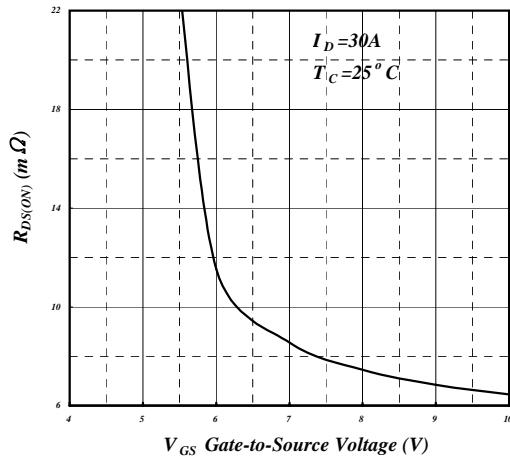
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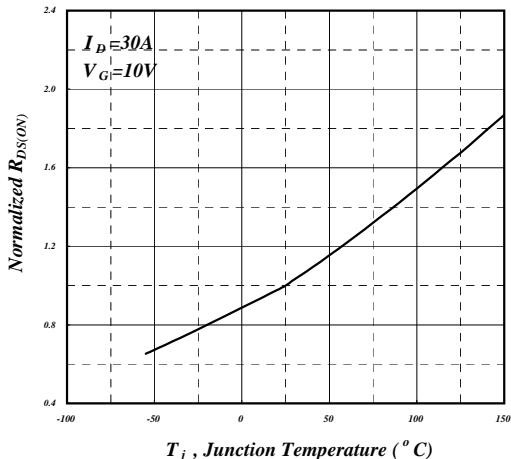
**Fig 1. Typical Output Characteristics**



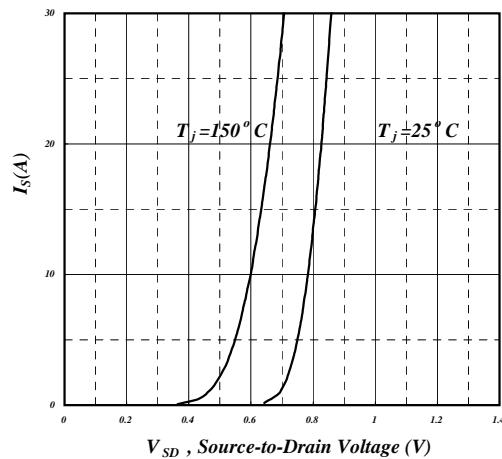
**Fig 2. Typical Output Characteristics**



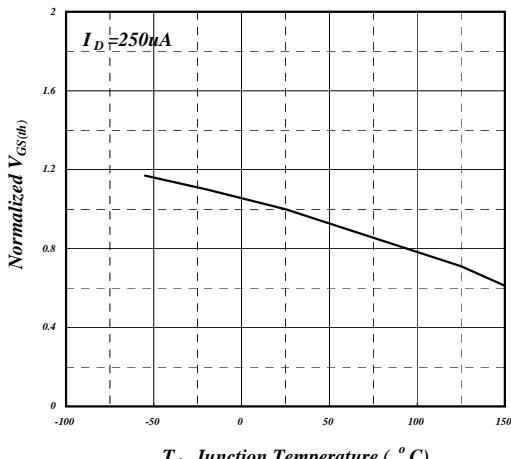
**Fig 3. On-Resistance v.s. Gate Voltage**



**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



**Fig 5. Forward Characteristic of Reverse Diode**



**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

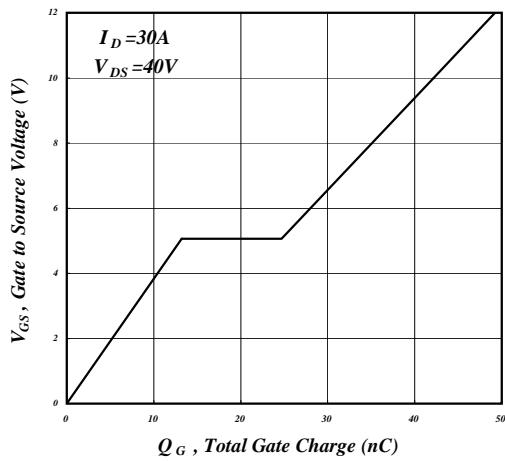


Fig 7. Gate Charge Characteristics

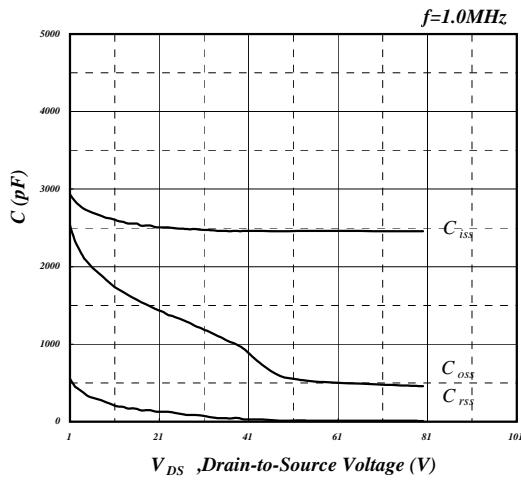


Fig 8. Typical Capacitance Characteristics

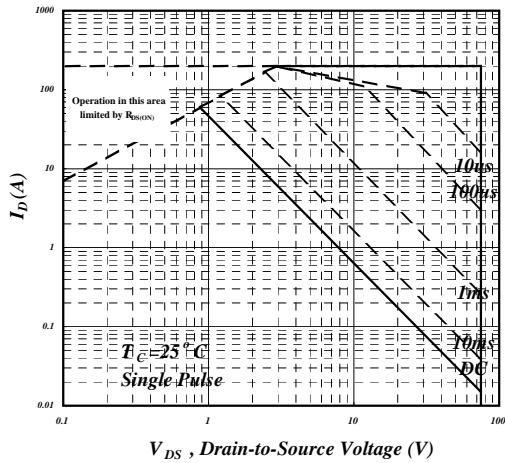


Fig 9. Maximum Safe Operating Area

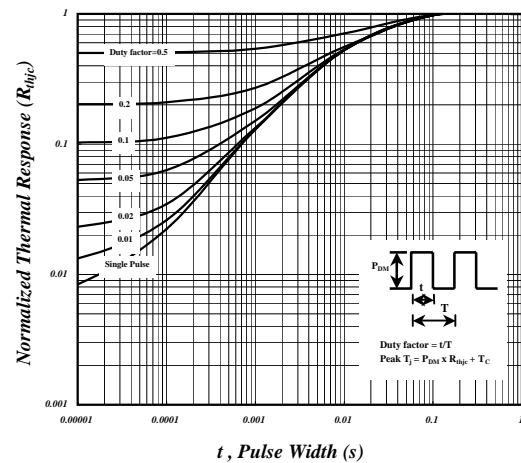


Fig 10. Effective Transient Thermal Impedance

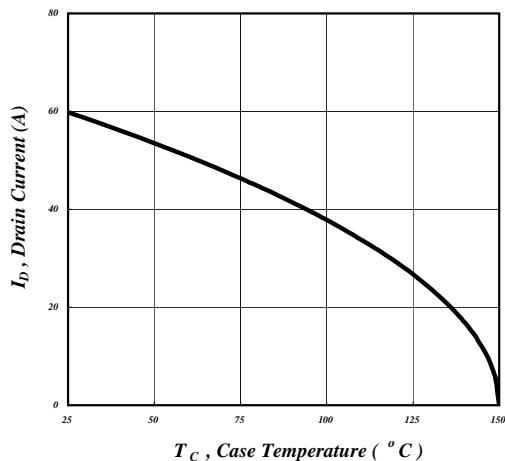


Fig 11. Drain Current v.s. Case Temperature

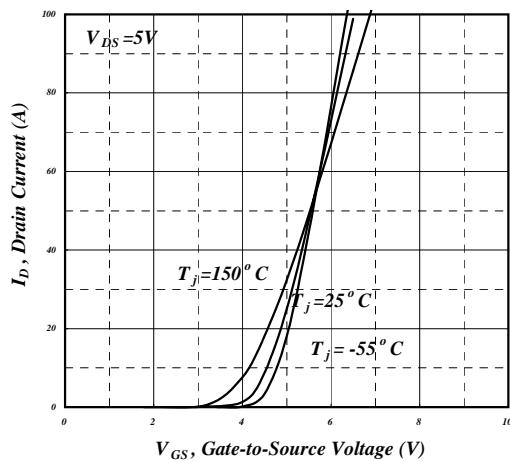
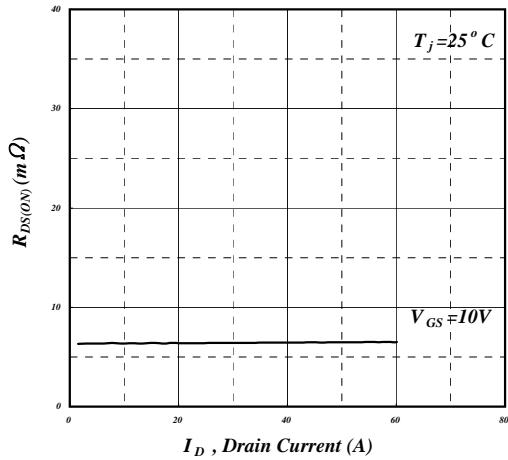
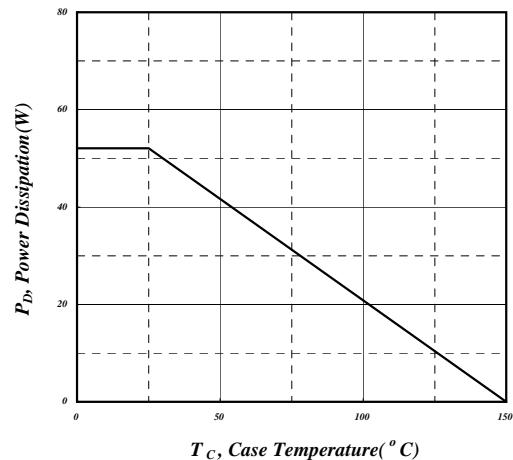


Fig 12. Transfer Characteristics



**Fig 13. Typ. Drain-Source on State Resistance**



**Fig 14. Total Power Dissipation**



**AP8N8R0H**

## **MARKING INFORMATION**

